

SYNCHROTRON POWDER DIFFRACTION

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Synchrotron Science for Cultural Heritage Materials, September 2010

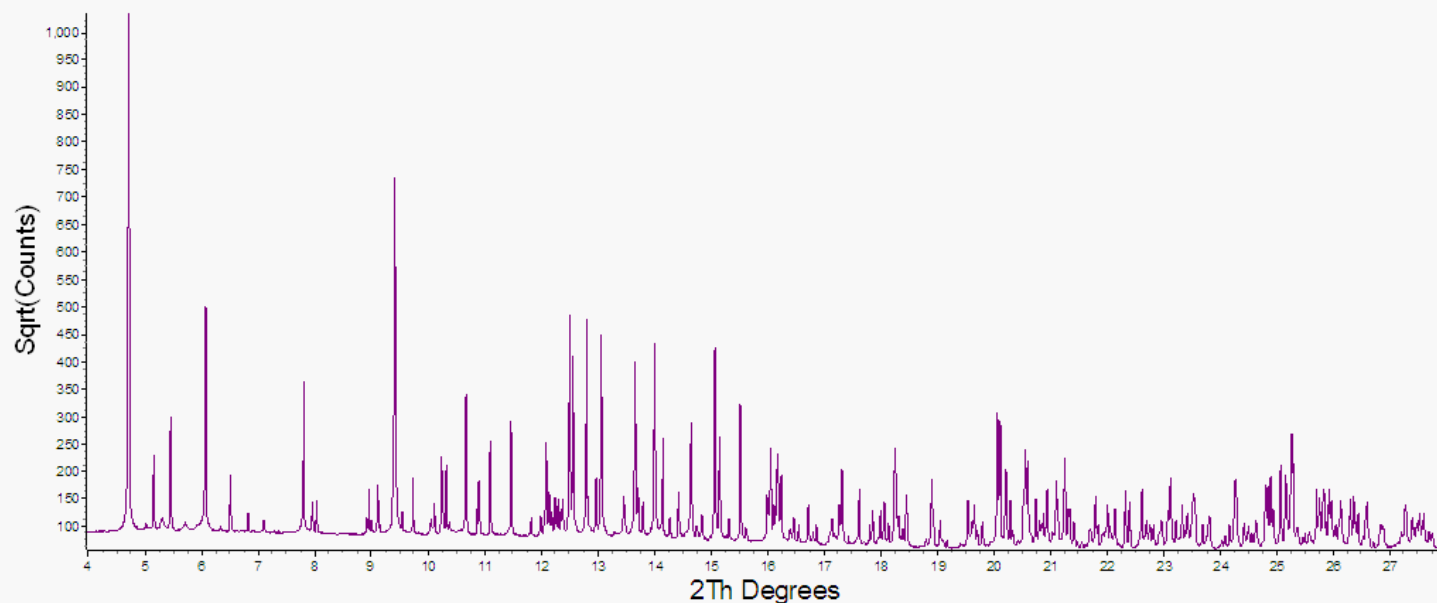
OUTLINE

Powder Diffraction

- Introduction & Applications
- Beamline Capabilities
- Data Quality

POWDER DIFFRACTION

- A technique for investigating atomic crystal structure
 - PD is not suitable for non-crystalline materials
- PD is not a spectroscopic technique
 - The peaks are not informative in isolation



APPLICATIONS OF POWDER DIFFRACTION

1. Phase identification
2. Quantitative phase analysis
3. *In situ* examination of reaction processes

e.g. effect of heat treatment

TRADITIONAL X-RAY SOURCES

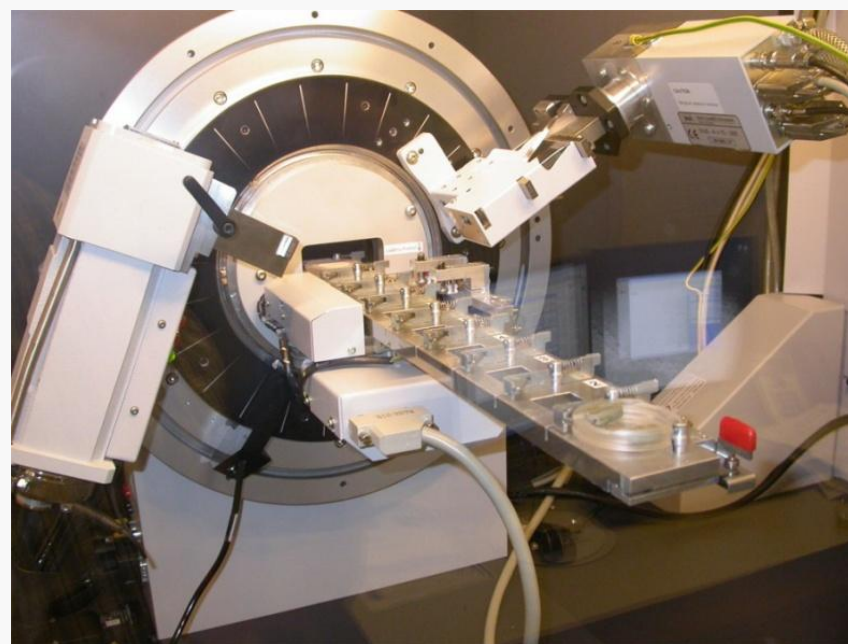
Vital for thorough studies

Advantages

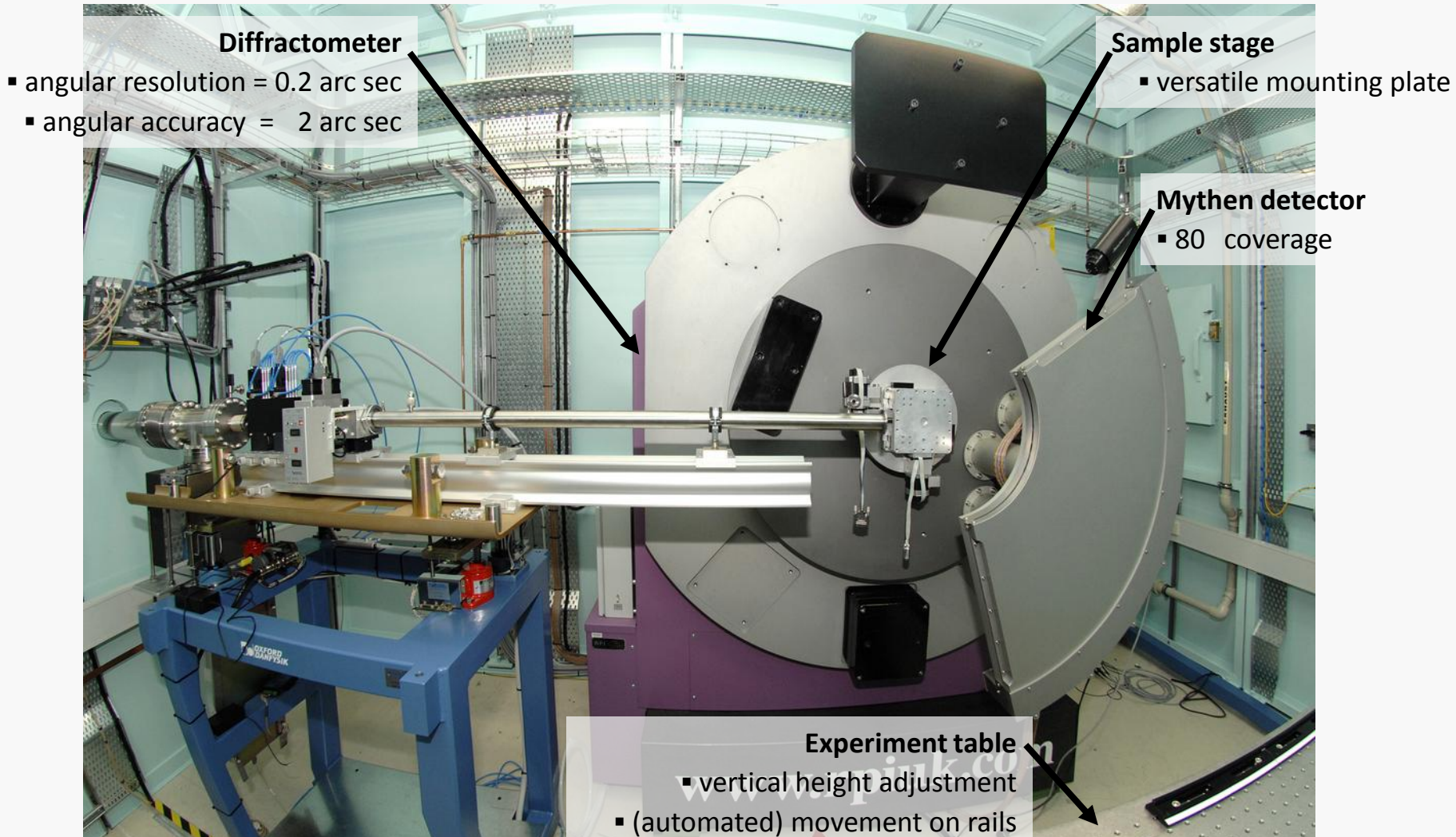
- Convenient to access
- Low cost
- Excellent for routine phase identification
- Quantitative analysis
- Some structure solution possible

Limitations

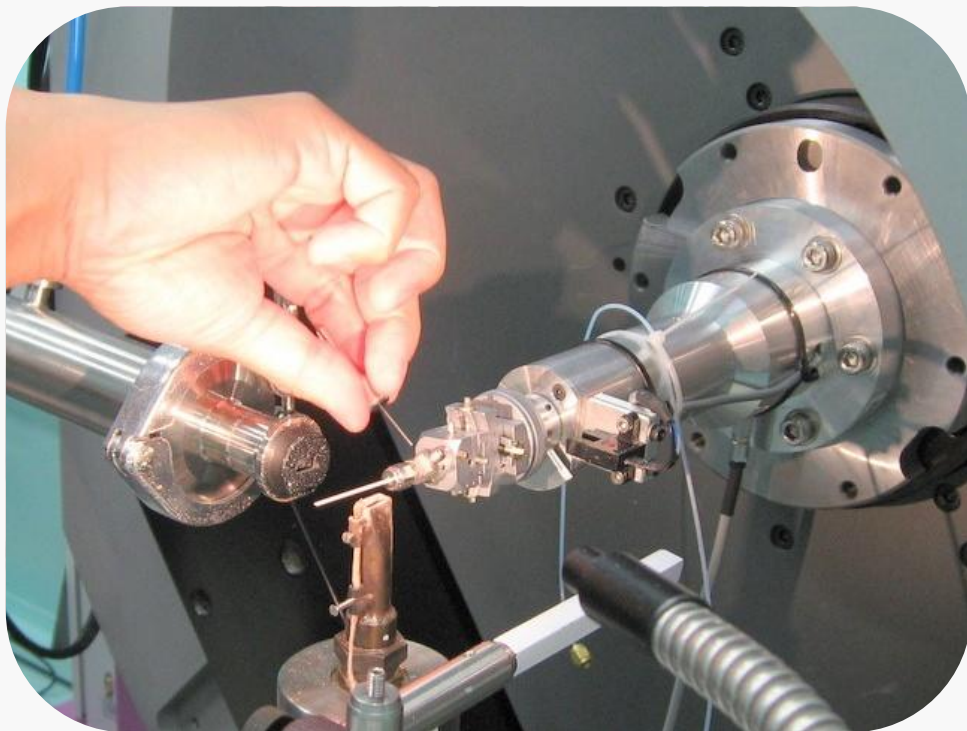
- Poor peak resolution
- Low intensity source
- Speed of data acquisition
- Limited sample ancillaries / stages



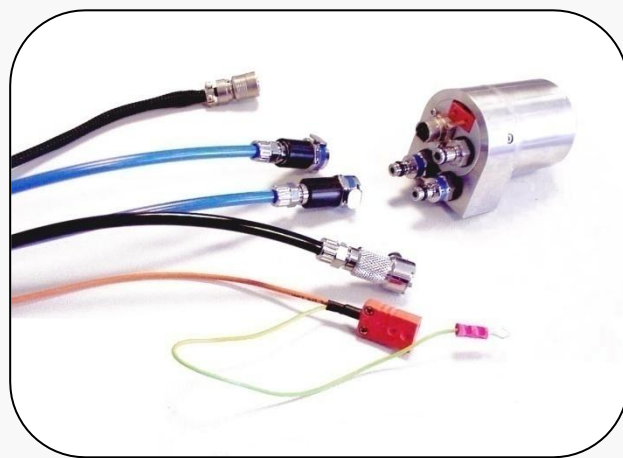
POWDER DIFFRACTION BEAMLINE END STATION



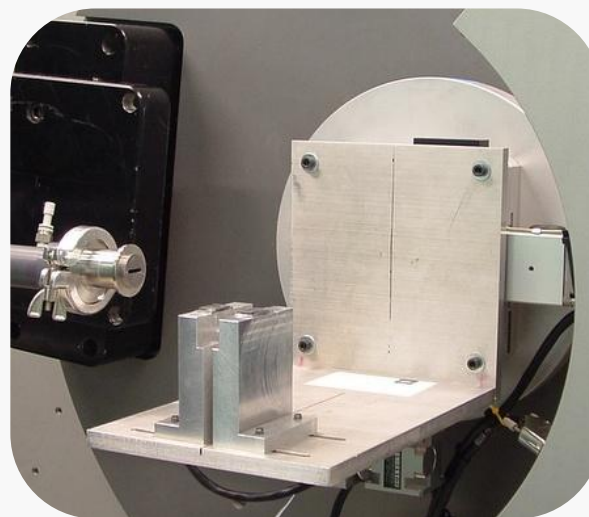
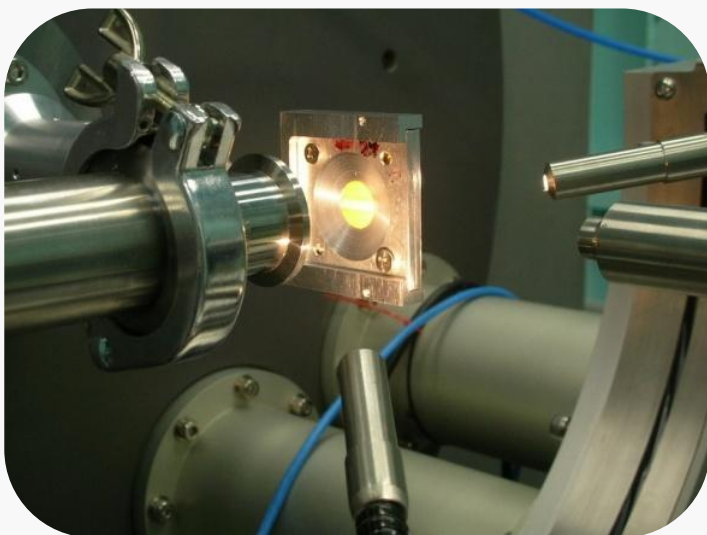
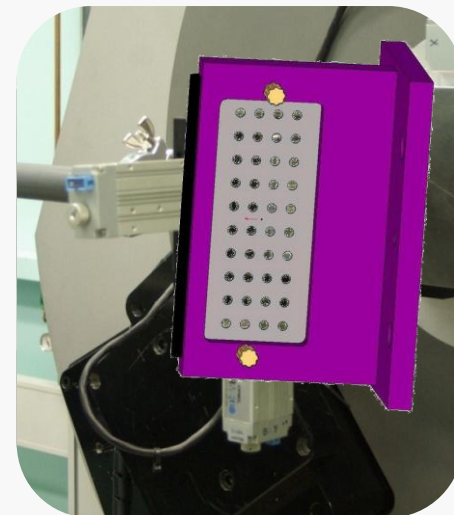
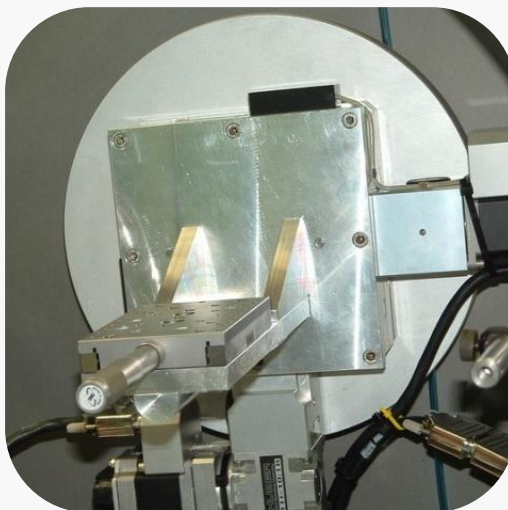
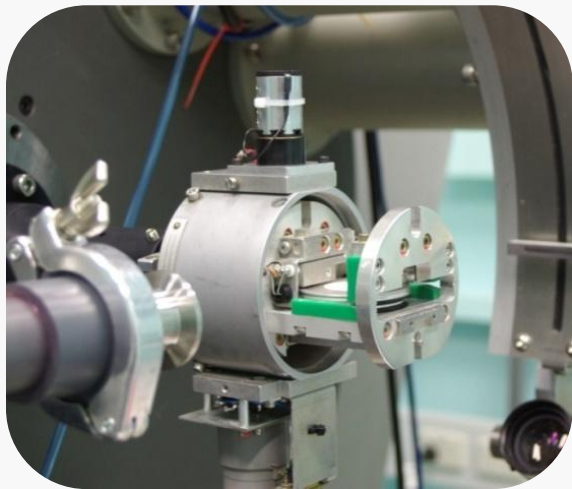
SAMPLE ANCILLARIES – CAPILLARY SAMPLES



Temperature range = 80 – 1,173 K



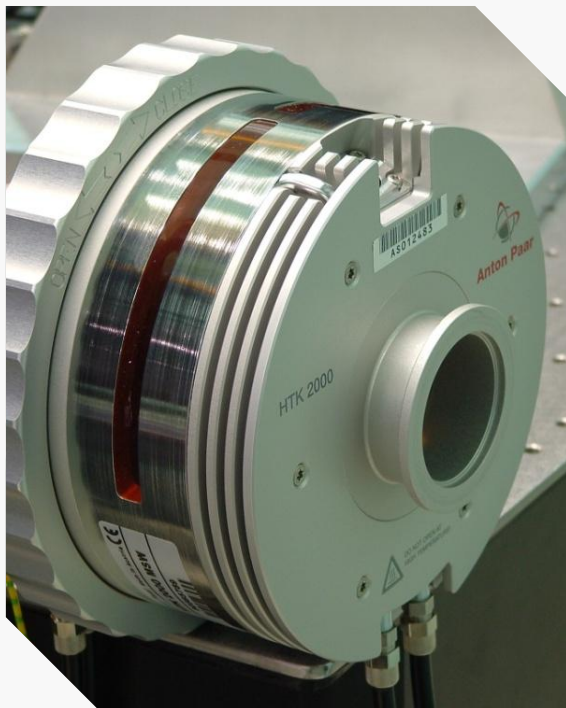
SAMPLE STAGES – VARIOUS MOUNTING METHODS



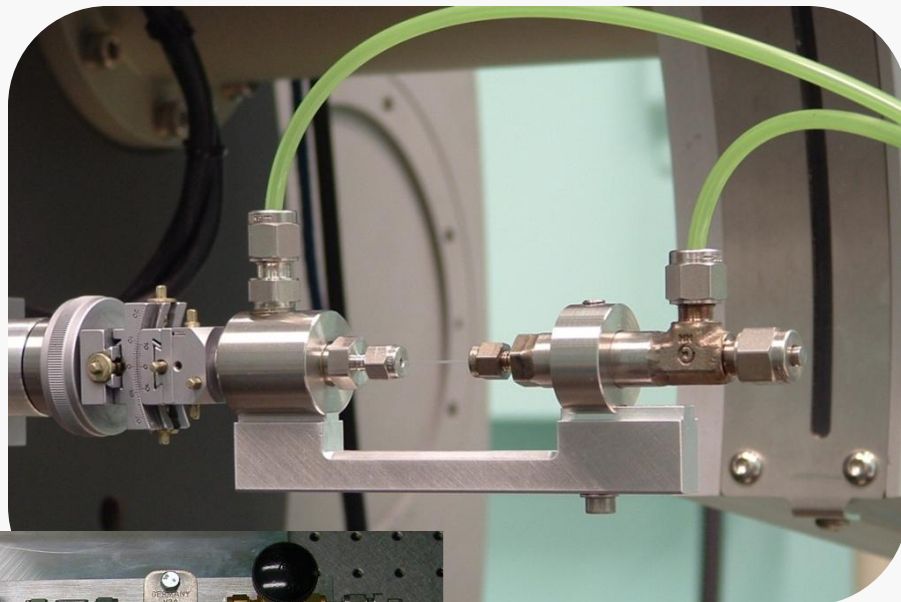
MECCANO & STICKY TAPE



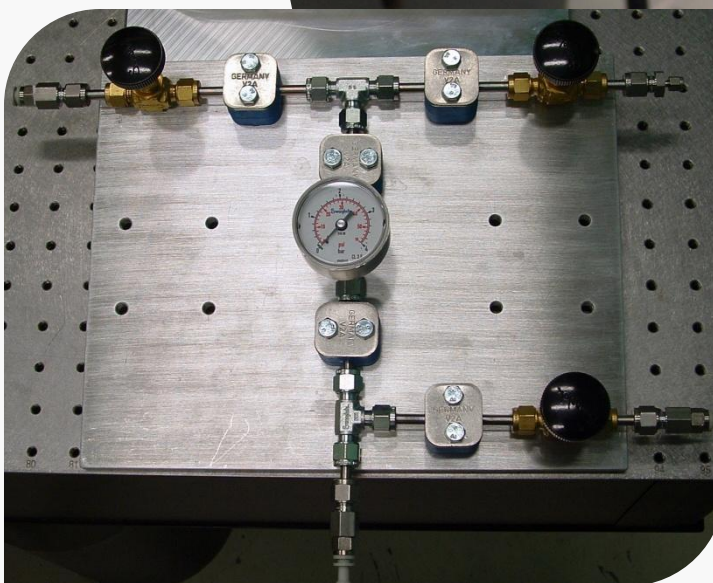
SAMPLE ANCILLARIES – FURNACE & GAS FLOW



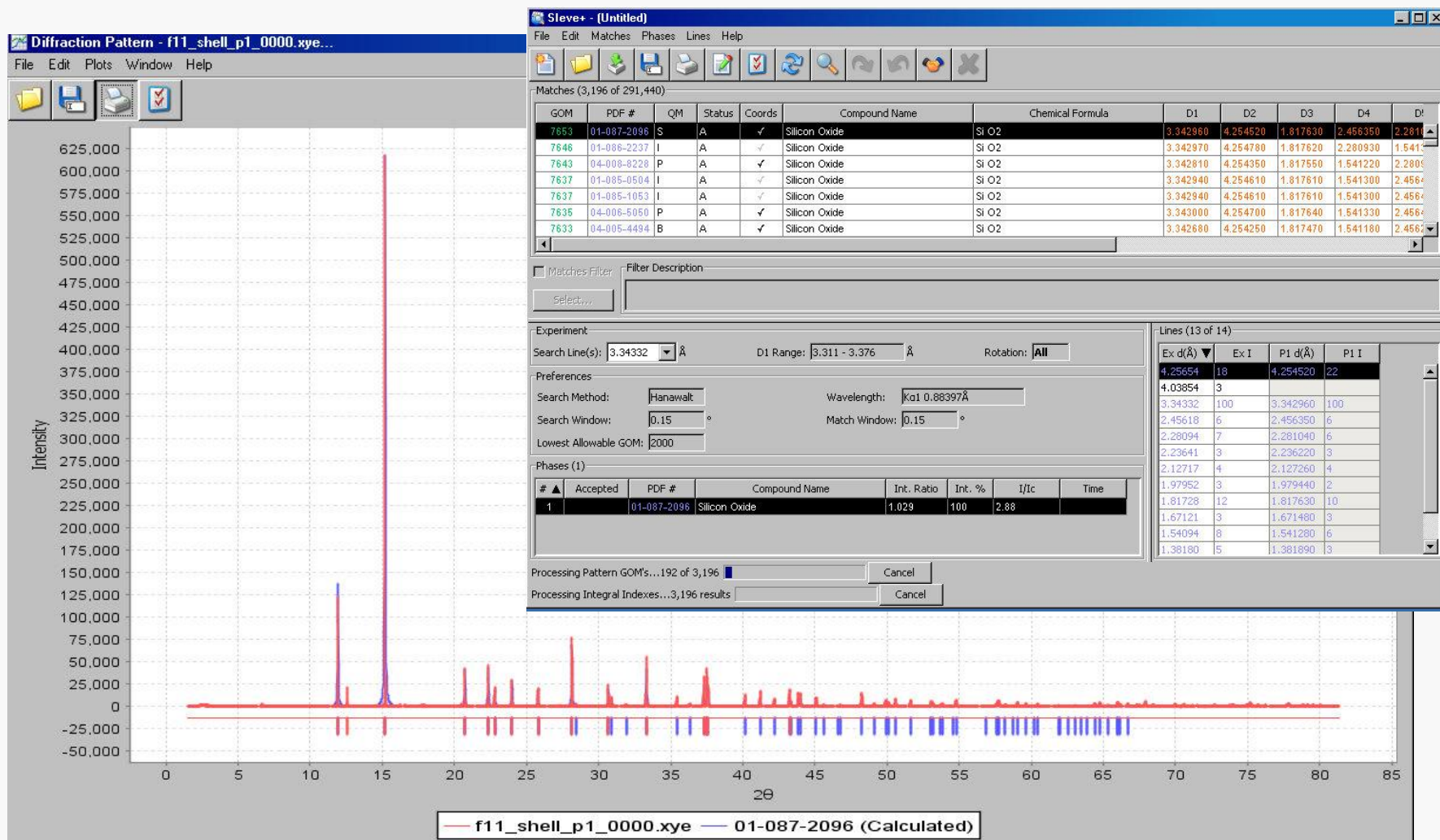
Furnace temperature
range = 298 – 2,573 K



Gas/vacuum cell



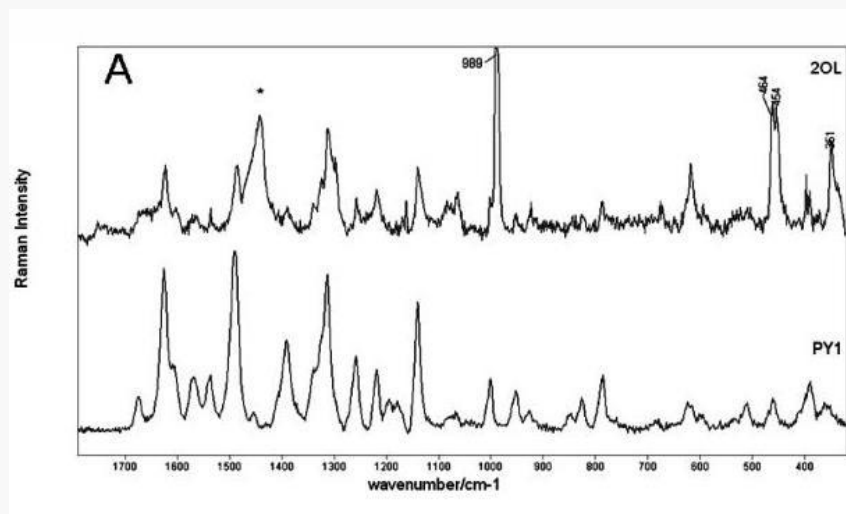
SEARCH / MATCH DATABASE



Combined X-ray Diffraction and Raman Identification of Synthetic Organic Pigments in Works of Art: From Powder Samples to Artists' Paints

L. B. Brostoff, S. A. Centeno, P. Ropret, P. Bythrow, and F. Pottier, *Anal. Chem.* 2009, **81**, 6096–6106

Raman



XRD

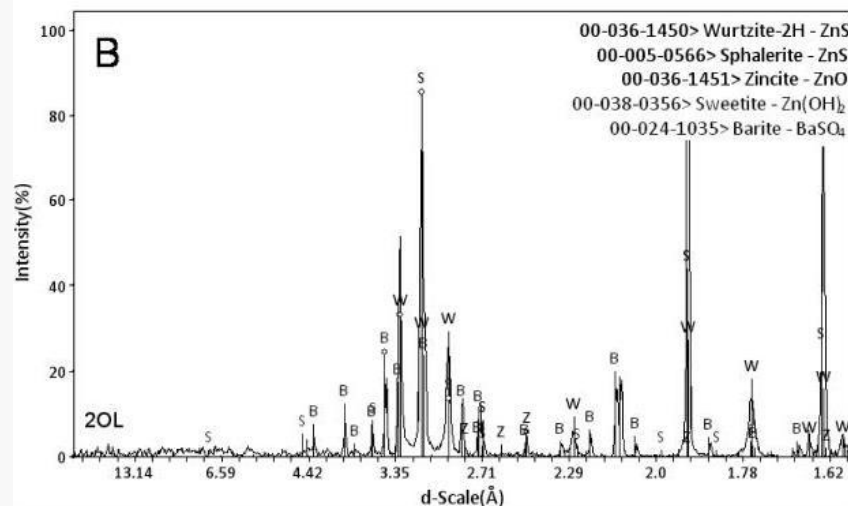
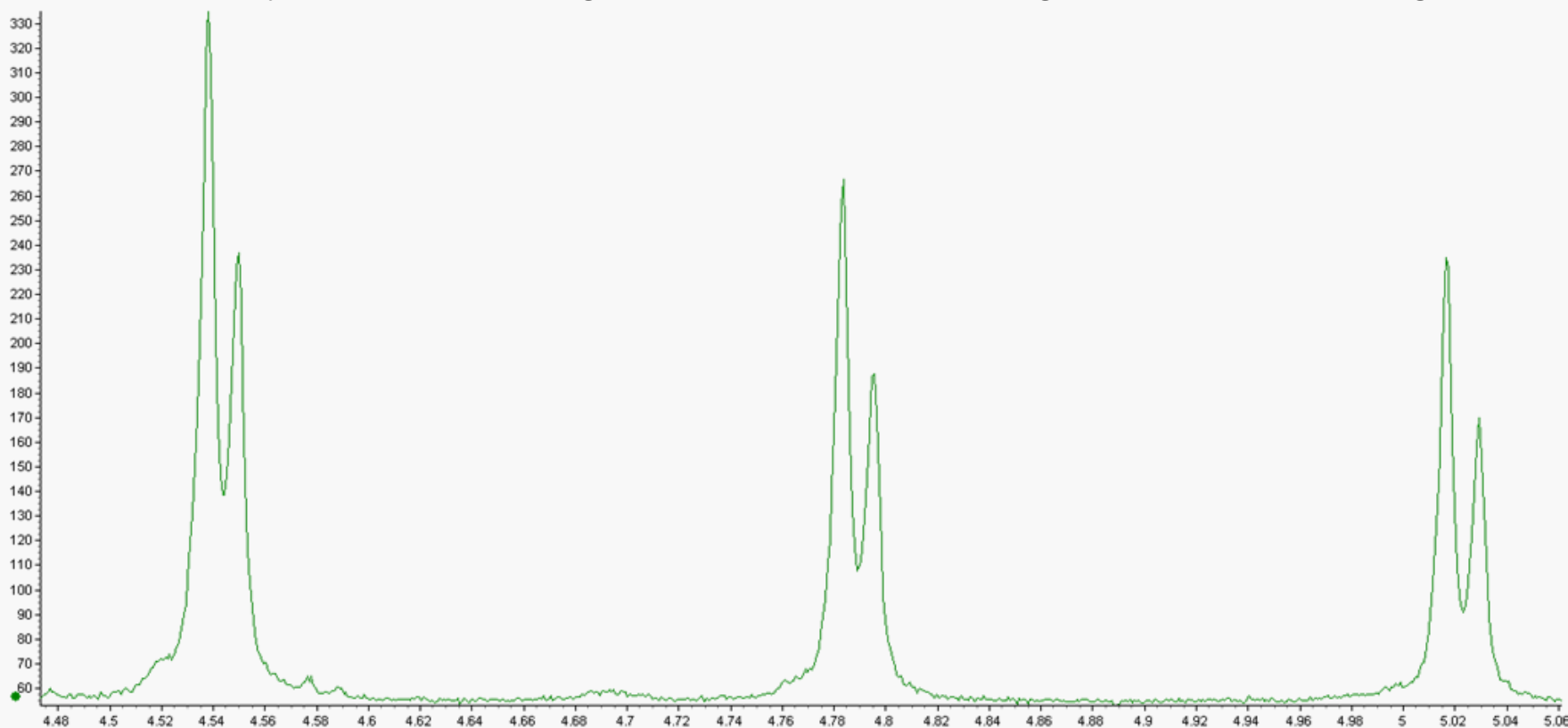


Figure 4. (A) Raman spectra of the oil bound sample 2OL (Lukas (Studio) Brillantgelb hell, top) and of a PY 1 reference sample (SunChemicals, bottom). Main bands are due to the extenders BaSO₄ (ca. 989 cm⁻¹, shown out of range, 464 and 454 cm⁻¹) and ZnS (ca. 351 cm⁻¹) indicated. The band at ca. 1440 cm⁻¹, marked by an asterisk, may arise from CH₂ deformations of the oil binder; $\lambda_0 = 785$ nm. (B) μ XRD pattern detail (Cr K α radiation) of paint sample 2OL, after background subtraction, with ICDD pattern matches shown in vertical bars (barite peaks marked with "B"; zincite peaks marked with "Z"; sweetite peaks marked with "S"; wurtzite peaks marked with "W"; sphalerite peaks marked with "S").

DATA QUALITY

Laboratory XRD Instrument

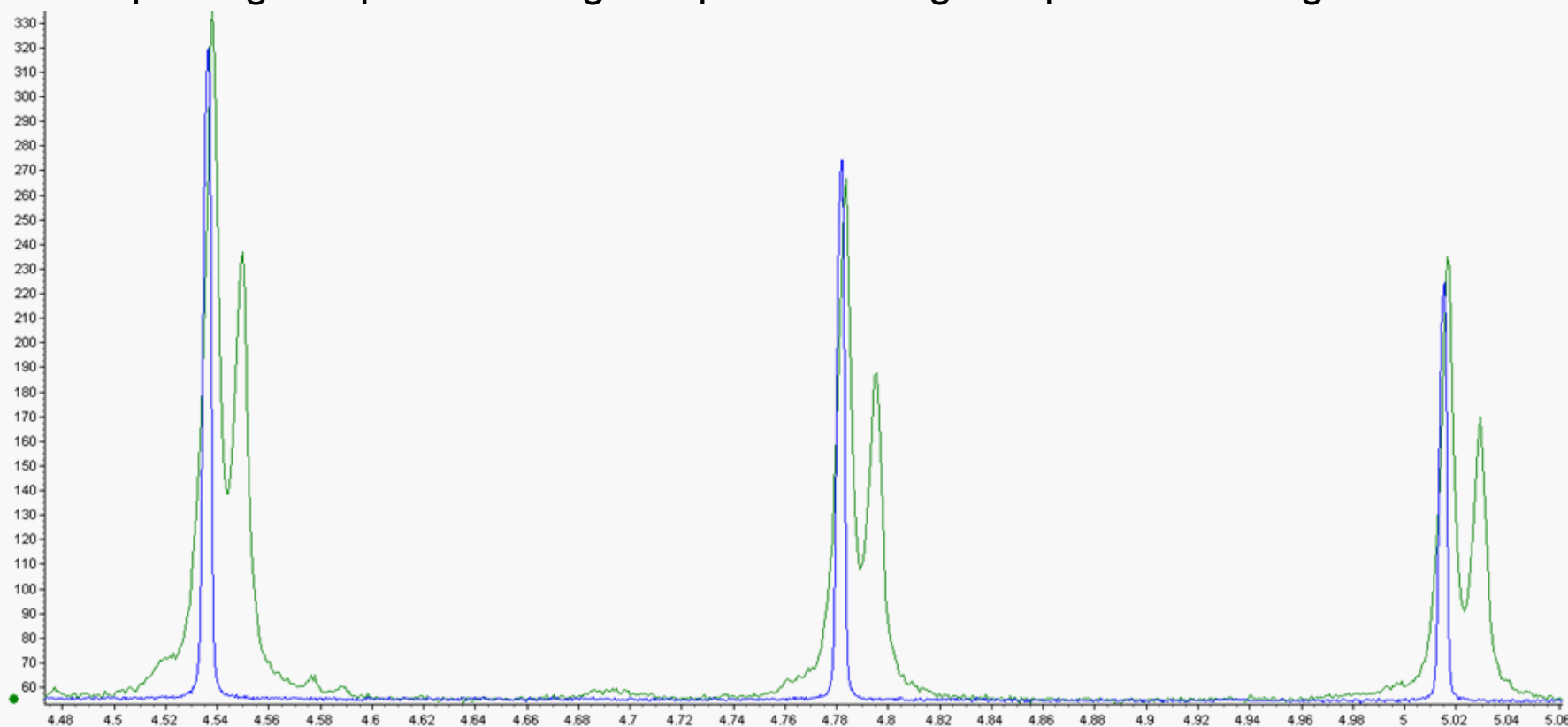
- Cu $K\alpha_{1,2}$
- Stationary sample – divergence in beam ensures good ‘powder average’



DATA QUALITY

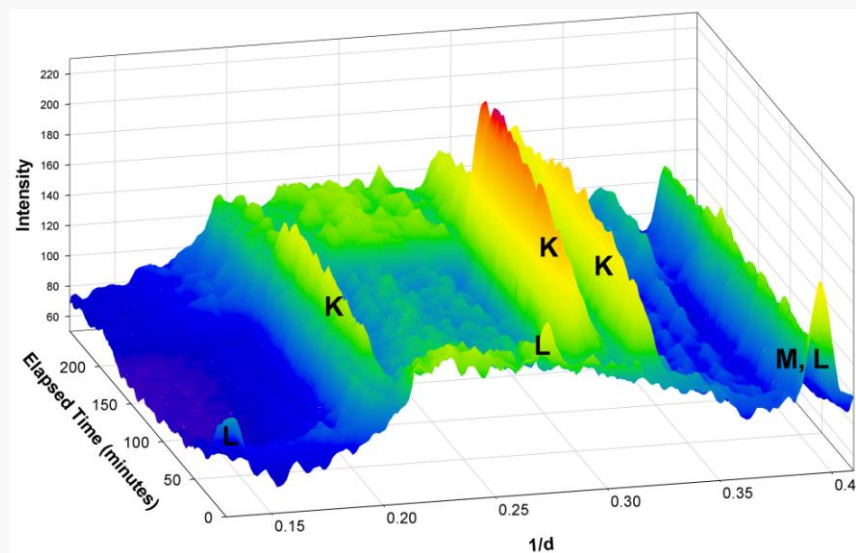
Synchrotron PD data overlaying laboratory data

- 0.3mm capillary
- Spinning sample – rotating sample ensures good ‘powder average’

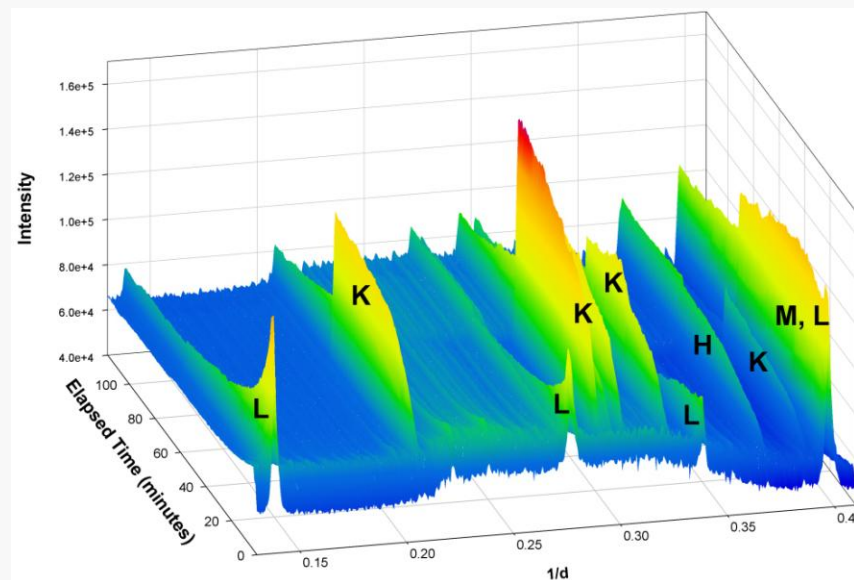


SIGNAL TO NOISE

Laboratory XRD



Synchrotron XRD



TAKE-HOME MESSAGE

Synchrotron powder diffraction

- Important tool for materials characterisation
- Non-destructive
- Flexible and tailored sample mounting options
- High resolution data
- High intensity X-rays
- Tunable, high energy X-rays

THANK YOU

